

# 2

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<b>FORM PTO-1449</b>				Attorney Docket: 1232-4421US1		Divisional of Serial No.: 09/025,409	
<b>INFORMATION DISCLOSURE CITATION</b>				Applicant: Uehara et al..			
				Filing Date: 9/19/00		Group Art Unit: UNKNOWN	
<b>U.S. PATENT DOCUMENTS</b>							
Examiner Initial		Document Number	Date	Name	Class	Sub-Class	Filing Date
K-cc	AA	5,593,537	1/14/97	Cote et al.	156	636.1	—
K-cc	AB	4,736,760	4/12/88	Coberly et al.	134	134	—
K-cc	AC	4,804,007	2/14/89	Bran	134	184	—
K-cc	AD	5,593,505	2/14/97	Erk et al.	134	1.3	—
K-cc	AE	3,964,957	6/22/76	Walsh	156	345	—
K-cc	AF	4,325,394	4/20/82	Reams	134	141	—
K-cc	AG	4,854,337	8/8/89	Bunkenburg et al.	134	184	—
K-cc	AH	5,286,657	2/15/94	Bran	437	9	—
K-cc	AI	5,327,921	7/12/94	Mokuo et al.	134	182	—
K-cc	AJ	5,791,357	8/11/98	Hasegawa	134	137	—
K-cc	AK	5,816,274	10/6/98	Bartram et al.	134	140	—
K-cc	AL	5,672,212	9/30/97	Manos	134	1.3	—
K-cc	AM	5,727,582	3/17/98	Terui	134	140	—
Ø	AN						
	AO						
<b>FOREIGN PATENT DOCUMENTS</b>							
K-cc	AP	8-117702A	5/1996	Japan	—	—	Abstract
K-cc	AQ	07-142439A	6/1995	Japan	—	—	Abstract
K-cc	AR	5-243203	9/21/93	Japan	—	—	Abstract
K-cc	AS	8-293478	11/5/96	Japan	—	—	Abstract
K-cc	AT	53-144265	12/15/78	Japan	—	—	<input type="checkbox"/> Yes <input checked="" type="checkbox"/> No <i>abstract</i>
<b>OTHER DOCUMENTS (Including Author, Title, Date, etc.)</b>							
	AU						
	AV						
	AW						
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP §609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.							
<i>K-cc - Cha - chis</i> <span style="float: right;">01-04-02</span>							

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U.S. PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Name	Class	Sub-Class	Filing Date
	AA						
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FOREIGN PATENT DOCUMENTS							
K-cc	AP	62-283632	9/12/87	Japan	—	—	<input type="checkbox"/> Yes <input checked="" type="checkbox"/> No
K-cc	AQ	1-187931	7/27/89	Japan	—	—	<input type="checkbox"/> Yes <input checked="" type="checkbox"/> No
K-cc	AR	1-304733	8/12/89	Japan	—	—	<input type="checkbox"/> Yes <input checked="" type="checkbox"/> No
K-cc	AS	3-62925	3/19/91	Japan	—	—	<input type="checkbox"/> Yes <input checked="" type="checkbox"/> No
K-cc	AT	3-257826	11/18/91	Japan	—	—	<input type="checkbox"/> Yes <input checked="" type="checkbox"/> No

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OTHER DOCUMENTS (Including Author, Title, Date, etc.)		
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K-cc - Uehara et al.

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	<b>Applicant:</b> Uehara et al..	
	<b>Filing Date:</b> 9/19/00	<b>Group Art Unit:</b> UNKNOWN

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U.S. PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Name	Class	Sub-Class	Filing Date
	AA						
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FOREIGN PATENT DOCUMENTS							
K-cc	AP	9-038079	2/21/97	Japan	—	—	<input checked="" type="checkbox"/> Yes <input type="checkbox"/> No
K-cc	AQ	9-038080	2/21/97	Japan	—	—	<input checked="" type="checkbox"/> Yes <input type="checkbox"/> No
K-cc	AR	0 319 806	6/14/89	Europe	—	—	<input type="checkbox"/> Yes <input type="checkbox"/> No
	AS						<input type="checkbox"/> Yes <input type="checkbox"/> No
	AT						<input type="checkbox"/> Yes <input type="checkbox"/> No

OTHER DOCUMENTS (Including Author, Title, Date, etc.)		
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	AV	
	AW	

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*K-cc* *Uehara* *01-04-07*



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PTO-1449				Attorney Docket: 1232-4421US1		Divisional of Serial No.: 09/664,715	
<b>INFORMATION DISCLOSURE CITATION</b>				Applicant: Uehara et al.			
				Filing Date: 9/19/00		Group Art Unit: UNKNOWN	
<b>U.S. PATENT DOCUMENTS</b>							
Examiner Initial		Document Number	Date	Name	Class	Sub-Class	Filing Date
	AA	5,327,921	7/12/94	Mokuo et al.	134	182	
	AB	4,191,295	3/4/1980	Tams, III.	211	41	
	AC						
	AD						
	AE						
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	AJ						
<b>FOREIGN PATENT DOCUMENTS</b>							
Examiner Initial		Patent No.	Date	Country	Class	Sub-class	English Translation
	AK	EP 740331	10/30/96	Europe			Yes
	AL	EP 319806	6/14/89	Europe			Yes
	AM	EP 694957	1/31/96	Europe			Yes
	AN	EP 554795	8/11/93	Europe			Yes
	AO	EP 3257826	11/18/91	Europe			Abstract
	AP	EP 1304733	12/8/89	Europe			Abstract
	AQ	EP 8316182	11/29/96	Europe			Abstract
	AR	FR 2626261	7/28/89	France			Abstract
	AS						
<b>OTHER DOCUMENTS (Including Author, Title, Date, etc.)</b>							
	AU	K. Sakaguchi, Et Al., "Extremely High Selective Etching Of Porous Si For Single Etch-Stop Bond-And-Etch-Back Silicon-on-Insulator, <i>Jpn. J. Appl. Phys.</i> , Vol. 34 (1995) pp.842-847, Part 1, No. 2B, February 1995					
	AV	Communication dated August 6, 2001 in EP 98102897 and Partial European Search Report					
	AW						
<small>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP §609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.</small>							

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( Replaced by Paper No.4 IDS.  
( see Paper No.4 IDS (Nov. 29, 2001)  
K-cc 1-4-02



<b>FORM PTO-1449</b>  <b>INFORMATION DISCLOSURE CITATION</b>	Attorney Docket: 1232-4421US1	Divisional of Serial No.: 09/664,715
	Applicant: Uehara et al.	
	Filing Date: 9/19/2000	Group Art Unit: 1746

**U.S. PATENT DOCUMENTS**

Examiner Initial		Document Number	Date	Name	Class	Sub-Class	Filing Date
K-cc	AA	5,327,921	7/12/94	Mokuo et al.	134	182	—
K-cc	AB	4,191,295	3/4/1980	Tams, III.	211	41	—
	AC						
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	AE						
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	AG						
	AJ						

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**FOREIGN PATENT DOCUMENTS**

Examiner Initial		Patent No.	Date	Country	Class	Sub-class	English Translation
K-cc	AK	EP 740331	10/30/96	Europe	—	—	Yes
K-cc	AL	EP 319806	6/14/89	Europe	—	—	Yes
K-cc	AM	EP 694957	1/31/96	Europe	—	—	Yes
K-cc	AN	EP 554795	8/11/93	Europe	—	—	Yes
K-cc	AO	JP 3-257826	11/18/91	Japan	—	—	Abstract
K-cc	AP	JP 1-304733	12/8/89	Japan	—	—	Abstract
K-cc	AQ	JP 8-316182	11/29/96	Japan	—	—	Abstract
K-cc	AR	FR 2626261	7/28/89	France	—	—	Abstract
	AS						

**OTHER DOCUMENTS (Including Author, Title, Date, etc.)**

K-cc	AU	K. Sakaguchi, Et Al., "Extremely High Selective Etching Of Porous Si For Single Etch-Stop Bond-And-Etch-Back Silicon-on-Insulator, <i>Jpn. J. Appl. Phys.</i> , Vol. 34 (1995) pp.842-847, Part 1, No. 2B, February 1995
K-cc	AV	Communication dated August 6, 2001 in EP 98102897 and Partial European Search Report
	AW	

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K-cc [Signature]

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<b>FORM PTO-1449</b>				<b>Attorney Docket:</b> 1232-4421US1		<b>Divisional of Serial No.:</b> 09/664,715	
<b><u>INFORMATION DISCLOSURE CITATION</u></b>				<b>Applicant:</b> Uehara et al.			
				<b>Filing Date:</b> 9/19/2000		<b>Group Art Unit:</b> 1746	
<b>U.S. PATENT DOCUMENTS</b>							
<b>Examiner Initial</b>		<b>Document Number</b>	<b>Date</b>	<b>Name</b>	<b>Class</b>	<b>Sub-Class</b>	<b>Filing Date</b>
K-CC	AA	4,854,337	8/8/1989	Bunkenburg et al.	134	184	—
K-CC	AB	2,702,260	2/15/1955	F. Massa	—	—	—
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	AD						
	AE						
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<b>FOREIGN PATENT DOCUMENTS</b>							
<b>Examiner Initial</b>		<b>Patent No.</b>	<b>Date</b>	<b>Country</b>	<b>Class</b>	<b>Sub-calss</b>	<b>English Translation</b>
	AK						
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	AP						
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	AS						
<b>OTHER DOCUMENTS (Including Author, Title, Date, etc.)</b>							
K-CC	AU	European Patent Office's Communication dated October 15, 2001, in EP 98102897 and a European Search Report.					
	AV						
	AW						
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K-CC - Uehara et al. 01-5-02							